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## Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

## **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1206
Number of Logic Elements/Cells	12060
Total RAM Bits	239616
Number of I/O	173
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c12q240i7

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

#### Dynamic Arithmetic Mode

The dynamic arithmetic mode is ideal for implementing adders, counters, accumulators, wide parity functions, and comparators. An LE in dynamic arithmetic mode uses four 2-input LUTs configurable as a dynamic adder/subtractor. The first two 2-input LUTs compute two summations based on a possible carry-in of 1 or 0; the other two LUTs generate carry outputs for the two chains of the carry select circuitry. As shown in Figure 2–7, the LAB carry-in signal selects either the carry-in0 or carry-in1 chain. The selected chain's logic level in turn determines which parallel sum is generated as a combinatorial or registered output. For example, when implementing an adder, the sum output is the selection of two possible calculated sums:

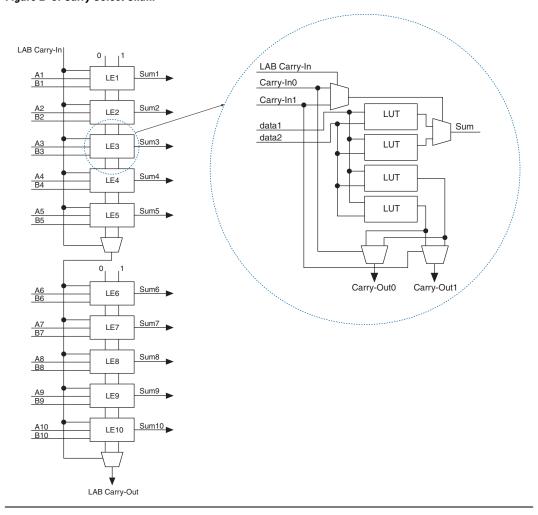
```
data1 + data2 + carry-in0
or
data1 + data2 + carry-in1
```

The other two LUTs use the data1 and data2 signals to generate two possible carry-out signals—one for a carry of 1 and the other for a carry of 0. The carry-in0 signal acts as the carry select for the carry-out0 output and carry-in1 acts as the carry select for the carry-out1 output. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

The dynamic arithmetic mode also offers clock enable, counter enable, synchronous up/down control, synchronous clear, synchronous load, and dynamic adder/subtractor options. The LAB local interconnect data inputs generate the counter enable and synchronous up/down control signals. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. The Quartus II software automatically places any registers that are not used by the counter into other LABs. The addnsub LAB-wide signal controls whether the LE acts as an adder or subtractor.

Figure 2–8 shows the carry-select circuitry in a LAB for a 10-bit full adder. One portion of the LUT generates the sum of two bits using the input signals and the appropriate carry-in bit; the sum is routed to the output of the LE. The register can be bypassed for simple adders or used for accumulator functions. Another portion of the LUT generates carry-out bits. A LAB-wide carry-in bit selects which chain is used for the addition of given inputs. The carry-in signal for each chain, carry-in0 or carry-in1, selects the carry-out to carry forward to the carry-in signal of the next-higher-order bit. The final carry-out signal is routed to an LE, where it is fed to local, row, or column interconnects.

Figure 2-8. Carry Select Chain



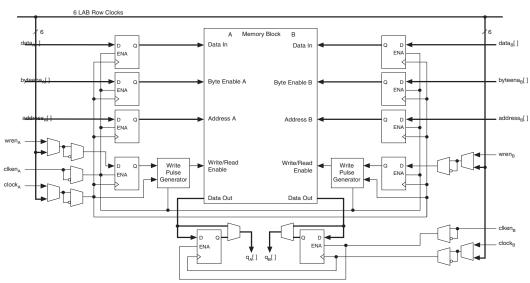


Figure 2–18. Input/Output Clock Mode in True Dual-Port Mode Notes (1), (2)

#### Notes to Figure 2–18:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

### **Single-Port Mode**

The M4K memory blocks also support single-port mode, used when simultaneous reads and writes are not required. See Figure 2–21. A single M4K memory block can support up to two single-port mode RAM blocks if each RAM block is less than or equal to 2K bits in size.

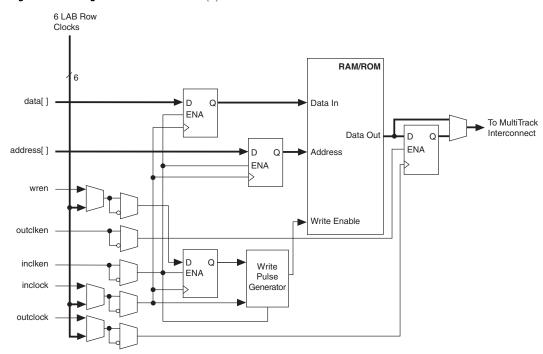


Figure 2–21. Single-Port Mode Note (1)

Note to Figure 2–21:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

## Global Clock Network and Phase-Locked Loops

Cyclone devices provide a global clock network and up to two PLLs for a complete clock management solution.

#### **Global Clock Network**

There are four dedicated clock pins (CLK[3..0], two pins on the left side and two pins on the right side) that drive the global clock network, as shown in Figure 2–22. PLL outputs, logic array, and dual-purpose clock (DPCLK[7..0]) pins can also drive the global clock network.

The eight global clock lines in the global clock network drive throughout the entire device. The global clock network can provide clocks for all resources within the device—IOEs, LEs, and memory blocks. The global clock lines can also be used for control signals, such as clock enables and synchronous or asynchronous clears fed from the external pin, or DQS signals for DDR SDRAM or FCRAM interfaces. Internal logic can also drive the global clock network for internally generated global clocks and asynchronous clears, clock enables, or other control signals with large fanout. Figure 2–22 shows the various sources that drive the global clock network.

DPCLK2 DPCLK3 Cyclone Device Global Clock Network 8 DPCLK1 \_ □ DPCLK4 From logic From logic array array CLK0 [ □ CLK2 PLL2 PLL1 CLK1 (3) □ CLK3 (3) (2) 2 DPCLK0 [ □ DPCLK5 DPCLK7 DPCLK6

Figure 2–22. Global Clock Generation Note (1)

#### *Notes to Figure 2–22:*

- (1) The EP1C3 device in the 100-pin TQFP package has five DPCLK pins (DPCLK2, DPCLK3, DPCLK4, DPCLK6, and DPCLK7).
- (2) EP1C3 devices only contain one PLL (PLL 1).
- (3) The EP1C3 device in the 100-pin TQFP package does not have dedicated clock pins CLK1 and CLK3.

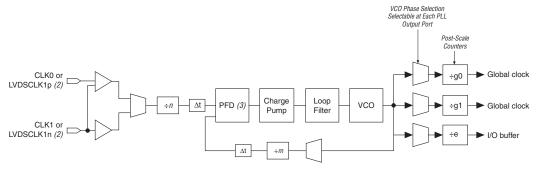
Table 2–6 shows the PLL features in Cyclone devices. Figure 2–25 shows a Cyclone PLL.

Table 2–6. Cyclone PLL Features								
Feature	PLL Support							
Clock multiplication and division	$m/(n \times post-scale counter)$ (1)							
Phase shift	Down to 125-ps increments (2), (3)							
Programmable duty cycle	Yes							
Number of internal clock outputs	2							
Number of external clock outputs	One differential or one single-ended (4)							

#### Notes to Table 2-6:

- (1) The *m* counter ranges from 2 to 32. The *n* counter and the post-scale counters range from 1 to 32.
- (2) The smallest phase shift is determined by the voltage-controlled oscillator (VCO) period divided by 8.
- (3) For degree increments, Cyclone devices can shift all output frequencies in increments of 45°. Smaller degree increments are possible depending on the frequency and divide parameters.
- (4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Figure 2–25. Cyclone PLL Note (1)



#### *Notes to Figure 2–25:*

- The EP1C3 device in the 100-pin TQFP package does not support external outputs or LVDS inputs. The EP1C6 device in the 144-pin TQFP package does not support external output from PLL2.
- (2) LVDS input is supported via the secondary function of the dedicated clock pins. For PLL 1, the CLK0 pin's secondary function is LVDSCLK1p and the CLK1 pin's secondary function is LVDSCLK1n. For PLL 2, the CLK2 pin's secondary function is LVDSCLK2p and the CLK3 pin's secondary function is LVDSCLK2n.
- (3) PFD: phase frequency detector.

Table 2–7. Global Clock Network Sources (Part 2 of 2)												
Source		GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7			
Dual-Purpose	DPCLK0 (3)	_	_	_	<b>✓</b>	_	_	_	_			
Clock Pins	DPCLK1 (3)	_	_	<b>✓</b>	_	_	_	_	_			
	DPCLK2	<b>✓</b>	_	_	_	_	_	_	_			
	DPCLK3	_	_	_	_	<b>✓</b>	_	_	_			
	DPCLK4		_	_	_	_		<b>✓</b>	_			
	DPCLK5 (3)	_	_	_	_	_	_	_	<b>✓</b>			
	DPCLK6	_	_	_	_	_	<b>✓</b>	_	_			
	DPCLK7	_	<b>✓</b>	_	_	_	_	_	_			

Notes to Table 2-7:

- (1) EP1C3 devices only have one PLL (PLL 1).
- (2) EP1C3 devices in the 100-pin TQFP package do not have dedicated clock pins CLK1 and CLK3.
- (3) EP1C3 devices in the 100-pin TQFP package do not have the DPCLK0, DPCLK1, or DPCLK5 pins.

#### **Clock Multiplication and Division**

Cyclone PLLs provide clock synthesis for PLL output ports using  $m/(n \times post$  scale counter) scaling factors. The input clock is divided by a pre-scale divider, n, and is then multiplied by the m feedback factor. The control loop drives the VCO to match  $f_{\rm IN} \times (m/n)$ . Each output port has a unique post-scale counter to divide down the high-frequency VCO. For multiple PLL outputs with different frequencies, the VCO is set to the least-common multiple of the output frequencies that meets its frequency specifications. Then, the post-scale dividers scale down the output frequency for each output port. For example, if the output frequencies required from one PLL are 33 and 66 MHz, the VCO is set to 330 MHz (the least-common multiple in the VCO's range).

Each PLL has one pre-scale divider, n, that can range in value from 1 to 32. Each PLL also has one multiply divider, m, that can range in value from 2 to 32. Global clock outputs have two post scale G dividers for global clock outputs, and external clock outputs have an E divider for external clock output, both ranging from 1 to 32. The Quartus II software automatically chooses the appropriate scaling factors according to the input frequency, multiplication, and division values entered.

## **Programmable Duty Cycle**

The programmable duty cycle allows PLLs to generate clock outputs with a variable duty cycle. This feature is supported on each PLL post-scale counter (g0, g1, e). The duty cycle setting is achieved by a low- and high-time count setting for the post-scale dividers. The Quartus II software uses the frequency input and the required multiply or divide rate to determine the duty cycle choices.

## **Control Signals**

There are three control signals for clearing and enabling PLLs and their outputs. You can use these signals to control PLL resynchronization and the ability to gate PLL output clocks for low-power applications.

The pllenable signal enables and disables PLLs. When the pllenable signal is low, the clock output ports are driven by ground and all the PLLs go out of lock. When the pllenable signal goes high again, the PLLs relock and resynchronize to the input clocks. An input pin or LE output can drive the pllenable signal.

The areset signals are reset/resynchronization inputs for each PLL. Cyclone devices can drive these input signals from input pins or from LEs. When areset is driven high, the PLL counters will reset, clearing the PLL output and placing the PLL out of lock. When driven low again, the PLL will resynchronize to its input as it relocks.

The pfdena signals control the phase frequency detector (PFD) output with a programmable gate. If you disable the PFD, the VCO will operate at its last set value of control voltage and frequency with some drift, and the system will continue running when the PLL goes out of lock or the input clock disables. By maintaining the last locked frequency, the system has time to store its current settings before shutting down. You can either use their own control signal or gated locked status signals to trigger the pfdena signal.



For more information about Cyclone PLLs, refer to *Using PLLs in Cyclone Devices* chapter in the *Cyclone Device Handbook*.

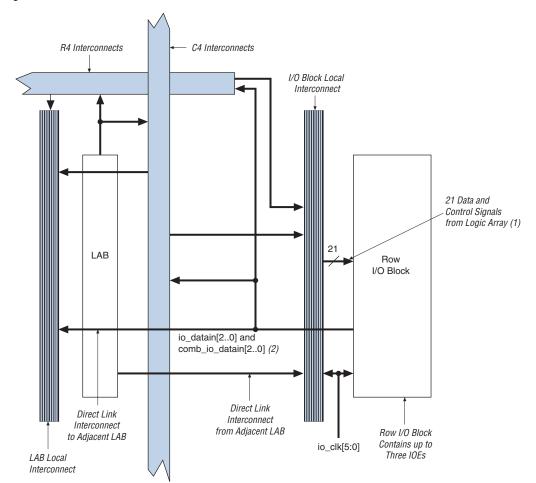


Figure 2-28. Row I/O Block Connection to the Interconnect

#### *Notes to Figure 2–28:*

- (1) The 21 data and control signals consist of three data out lines, io\_dataout[2..0], three output enables, io\_coe[2..0], three input clock enables, io\_cce\_in[2..0], three output clock enables, io\_cce\_out[2..0], three clocks, io\_cclk[2..0], three asynchronous clear signals, io\_caclr[2..0], and three synchronous clear signals, io\_csclr[2..0].
- (2) Each of the three IOEs in the row I/O block can have one io\_datain input (combinatorial or registered) and one comb\_io\_datain (combinatorial) input.

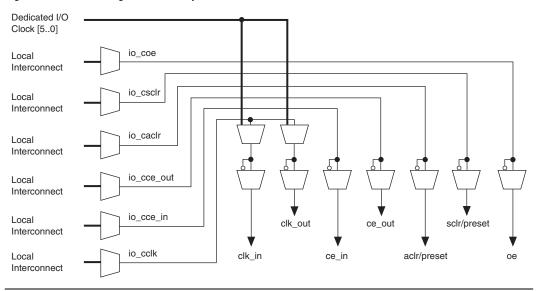


Figure 2-31. Control Signal Selection per IOE

In normal bidirectional operation, you can use the input register for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register is available for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from the local interconnect in the associated LAB, dedicated I/O clocks, or the column and row interconnects. Figure 2–32 shows the IOE in bidirectional configuration.

of the standard. Using minimum settings provides signal slew rate control to reduce system noise and signal overshoot. Table 2–11 shows the possible settings for the I/O standards with drive strength control.

Table 2–11. Programmable Drive Strength Note (1)							
I/O Standard	I <sub>OH</sub> /I <sub>OL</sub> Current Strength Setting (mA)						
LVTTL (3.3 V)	4						
	8						
	12						
	16						
	24(2)						
LVCMOS (3.3 V)	2						
	4						
	8						
	12(2)						
LVTTL (2.5 V)	2						
	8						
	12						
	16(2)						
LVTTL (1.8 V)	2						
	8						
	12(2)						
LVCMOS (1.5 V)	2						
	4						
	8(2)						

#### *Notes to Table 2–11:*

- SSTL-3 class I and II, SSTL-2 class I and II, and 3.3-V PCI I/O Standards do not support programmable drive strength.
- (2) This is the default current strength setting in the Quartus II software.

## **Open-Drain Output**

Cyclone devices provide an optional open-drain (equivalent to an open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write-enable signals) that can be asserted by any of several devices.

The Cyclone  $V_{\rm CCINT}$  pins must always be connected to a 1.5-V power supply. If the  $V_{\rm CCINT}$  level is 1.5 V, then input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The  $V_{\rm CCIO}$  pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (i.e., when  $V_{\rm CCIO}$  pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When  $V_{\rm CCIO}$  pins are connected to a 3.3-V power supply, the output high is 3.3-V and is compatible with 3.3-V or 5.0-V systems. Table 2–14 summarizes Cyclone MultiVolt I/O support.

Table 2–14. Cyclone MultiVolt I/O Support Note (1)											
V (V)		Ir	nput Sign	al			0ι	ıtput Sigr	nal		
V <sub>CCIO</sub> (V)	1.5 V 1.8 V			3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	
1.5	<b>✓</b>	<b>✓</b>	<b>√</b> (2)	<b>√</b> (2)	_	<b>✓</b>	_	_	_	_	
1.8	<b>✓</b>	<b>✓</b>	<b>√</b> (2)	<b>√</b> (2)	_	<b>√</b> (3)	<b>✓</b>	_	_	_	
2.5	_	_	<b>✓</b>	<b>✓</b>	_	<b>√</b> (5)	<b>√</b> (5)	<b>✓</b>	_	_	
3.3	_	_	<b>√</b> (4)	<b>✓</b>	<b>√</b> (6)	<b>√</b> (7)	<b>√</b> (7)	<b>√</b> (7)	<b>✓</b>	<b>√</b> (8)	

#### Notes to Table 2-14:

- (1) The PCI clamping diode must be disabled to drive an input with voltages higher than V<sub>CCIO</sub>.
- (2) When V<sub>CCIO</sub> = 1.5-V or 1.8-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected. Turn on Allow voltage overdrive for LVTTL / LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combinations.
- (3) When  $V_{CCIO} = 1.8$ -V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
- (4) When  $V_{CCIO} = 3.3$ -V and a 2.5-V input signal feeds an input pin, the  $V_{CCIO}$  supply current will be slightly larger than expected.
- (5) When V<sub>CCIO</sub> = 2.5-V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
- (6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (7) When V<sub>CCIO</sub> = 3.3-V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
- (8) When  $V_{CCIO} = 3.3$ -V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

## Power Sequencing and Hot Socketing

Because Cyclone devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the  $V_{\text{CCIO}}$  and  $V_{\text{CCINT}}$  power supplies may be powered in any order.

Signals can be driven into Cyclone devices before and during power up without damaging the device. In addition, Cyclone devices do not drive out during power up. Once operating conditions are reached and the device is configured, Cyclone devices operate as specified by the user.

Typically, the user-mode current during device operation is lower than the power-up current in Table 4–17. Altera recommends using the Cyclone Power Calculator, available on the Altera web site, to estimate the user-mode  $I_{\text{CCINT}}$  consumption and then select power supplies or regulators based on the higher value.

## **Timing Model**

The DirectDrive technology and MultiTrack interconnect ensure predictable performance, accurate simulation, and accurate timing analysis across all Cyclone device densities and speed grades. This section describes and specifies the performance, internal, external, and PLL timing specifications.

All specifications are representative of worst-case supply voltage and junction temperature conditions.

## **Preliminary and Final Timing**

Timing models can have either preliminary or final status. The Quartus® II software issues an informational message during the design compilation if the timing models are preliminary. Table 4–18 shows the status of the Cyclone device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 4–18. Cyclone Device Timing Model Status									
Device Preliminary Final									
EP1C3	_	✓							
EP1C4	_	✓							
EP1C6	_	✓							
EP1C12	_	✓							
EP1C20	_	✓							

Symbol	-	6	-	7	-	Unit	
	Min	Max	Min	Max	Min	Max	Unit
t <sub>M4KRC</sub>	_	4,379		5,035		5,691	ps
t <sub>M4KWC</sub>	_	2,910		3,346		3,783	ps
t <sub>M4KWERESU</sub>	72	_	82	_	93	_	ps
t <sub>M4KWEREH</sub>	43	_	49	_	55	_	ps
t <sub>M4KBESU</sub>	72	_	82	_	93	_	ps
t <sub>M4KBEH</sub>	43	_	49	_	55	_	ps
t <sub>M4KDATAASU</sub>	72	_	82	_	93	_	ps
t <sub>M4KDATAAH</sub>	43	_	49	_	55	_	ps
t <sub>M4KADDRASU</sub>	72	_	82	_	93	_	ps
t <sub>M4KADDRAH</sub>	43	_	49	_	55	_	ps
t <sub>M4KDATABSU</sub>	72	_	82	_	93	_	ps
t <sub>M4KDATABH</sub>	43	_	49	_	55	_	ps
t <sub>M4KADDRBSU</sub>	72	_	82	_	93	_	ps
t <sub>M4KADDRBH</sub>	43	_	49	_	55	_	ps
t <sub>M4KDATACO1</sub>	_	621	_	714	_	807	ps
t <sub>M4KDATACO2</sub>	_	4,351	_	5,003	_	5,656	ps
t <sub>M4KCLKHL</sub>	1,234	_	1,562	_	1,818	_	ps
t <sub>M4KCLR</sub>	286	_	328		371		ps

Table 4–28. Routing Delay Internal Timing Microparameters											
Symbol	-	6	-	7	-	8	llm:4				
	Min	Max	Min	Max	Min	Max	Unit				
t <sub>R4</sub>	_	261	_	300	_	339	ps				
t <sub>C4</sub>	_	338	_	388	_	439	ps				
t <sub>LOCAL</sub>	_	244	_	281	_	318	ps				

## **External Timing Parameters**

External timing parameters are specified by device density and speed grade. Figure 4–2 shows the timing model for bidirectional IOE pin timing. All registers are within the IOE.

Table 4–29. C	yclone Global Clock External I/O Timing Parameters No	tes (1), (2) (Part 2 of 2)
Symbol	Parameter	Conditions
toutcople	Clock-to-output delay output or bidirectional pin using IOE output register with global clock enhanced PLL with default phase setting	C <sub>LOAD</sub> = 10 pF

#### Notes to Table 4-29:

- (1) These timing parameters are sample-tested only.
- (2) These timing parameters are for IOE pins using a 3.3-V LVTTL, 24-mA setting. Designers should use the Quartus II software to verify the external timing for any pin.

Tables 4–30 through 4–31 show the external timing parameters on column and row pins for EP1C3 devices.

Table 4–30. EP1C3 Column Pin Global Clock External I/O Timing Parameters												
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee							
Symbol	Min	Max	Min	Max	Min	Max	Unit					
t <sub>INSU</sub>	3.085	_	3.547	_	4.009	_	ns					
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns					
toutco	2.000	4.073	2.000	4.682	2.000	5.295	ns					
t <sub>INSUPLL</sub>	1.795	_	2.063	_	2.332	_	ns					
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns					
toutcople	0.500	2.306	0.500	2.651	0.500	2.998	ns					

Table 4–31. EP1C3 Row Pin Global Clock External I/O Timing Parameters											
Symbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	1114					
	Min	Max	Min	Max	Min	Max	Unit				
t <sub>INSU</sub>	3.157	_	3.630	_	4.103	_	ns				
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns				
t <sub>outco</sub>	2.000	3.984	2.000	4.580	2.000	5.180	ns				
t <sub>INSUPLL</sub>	1.867	_	2.146	_	2.426	_	ns				
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns				
toutcople	0.500	2.217	0.500	2.549	0.500	2.883	ns				

Tables 4–32 through 4–33 show the external timing parameters on column and row pins for EP1C4 devices.

Table 4–32. EP1C4 Column Pin Global Clock External I/O Timing Parameters Note (1)

Symbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Unit	
	Min	Max	Min	Max	Min	Max	UIIIL
t <sub>INSU</sub>	2.471	_	2.841	_	3.210	_	ns
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns
toutco	2.000	3.937	2.000	4.526	2.000	5.119	ns
t <sub>INSUPLL</sub>	1.471	_	1.690	_	1.910	_	ns
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.080	0.500	2.392	0.500	2.705	ns

Table 4–33. EP1C4 Row Pin Global Clock External I/O Timing Parameters Note (1)

Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	linit	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t <sub>INSU</sub>	2.600	_	2.990	_	3.379	_	ns
t <sub>INH</sub>	0.000	_	0.000	_	0.000	_	ns
t <sub>outco</sub>	2.000	3.991	2.000	4.388	2.000	5.189	ns
t <sub>INSUPLL</sub>	1.300	_	1.494	_	1.689	_	ns
t <sub>INHPLL</sub>	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.234	0.500	2.569	0.500	2.905	ns

*Note to Tables 4–32 and 4–33:* 

<sup>(1)</sup> Contact Altera Applications for EP1C4 device timing parameters.

Table 4–40. Cyclone I/O Standard Column Pin Input Delay Adders (Part 2 of 2)								
I/O Standard	-6 Spee	-6 Speed Grade		d Grade	-8 Speed Grade		Hnit	
I/O Standard	Min	Max	Min	Max	Min	Max	- Unit	
SSTL-2 class II		-278	_	-320	_	-362	ps	
LVDS		-261	_	-301	_	-340	ps	

Table 4–41. Cyclone I/O Standard Row Pin Input Delay Adders							
1/0 04	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		1114
I/O Standard	Min	Max	Min	Max	Min	Max	Unit
LVCMOS	_	0	_	0	_	0	ps
3.3-V LVTTL	_	0	_	0	_	0	ps
2.5-V LVTTL	_	27	_	31	_	35	ps
1.8-V LVTTL	_	182	_	209	_	236	ps
1.5-V LVTTL	_	278	_	319	_	361	ps
3.3-V PCI (1)	_	0	_	0	_	0	ps
SSTL-3 class I	_	-250	_	-288	_	-325	ps
SSTL-3 class II	_	-250	_	-288	_	-325	ps
SSTL-2 class I	_	-278	_	-320	_	-362	ps
SSTL-2 class II	_	-278	_	-320	_	-362	ps
LVDS	_	-261	_	-301	_	-340	ps

Ctone	loud	-6 Speed Grade		-7 Spe	-7 Speed Grade		ed Grade	Unit
Standard		Min Max		Min	Max	Min	Max	
LVCMOS	2 mA	_	0	_	0	_	0	ps
	4 mA	_	-489	_	-563	_	-636	ps
	8 mA	_	-855	_	-984	_	-1,112	ps
	12 mA	_	-993	_	-1,142	_	-1,291	ps
3.3-V LVTTL	4 mA	_	0	_	0	_	0	ps
	8 mA	_	-347	_	-400	_	-452	ps
	12 mA	_	-858	_	-987	_	-1,116	ps
	16 mA	_	-819	_	-942	_	-1,065	ps
	24 mA	_	-993	_	-1,142	_	-1,291	ps

Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)								
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		1114
		Min	Max	Min	Max	Min	Max	Unit
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
SSTL-3 class I		_	1,390	_	1,598	_	1,807	ps
SSTL-3 class I	I	_	989	_	1,137	_	1,285	ps
SSTL-2 class I		_	1,965	_	2,259	_	2,554	ps
SSTL-2 class I	I	_	1,692	_	1,945		2,199	ps
LVDS	·	_	802	_	922	_	1,042	ps

		-6 Snor	ed Grade	-7 Sno	ad Grada	-8 Sno	ed Grade	
I/O Standard		-o spec	tu ulaut	-7 Speed Grade		-o she	u uraue	Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
3.3-V PCI		_	923	_	1,061	_	1,199	ps

# Referenced Document

This chapter references the following documents:

- Cyclone Architecture chapter in the Cyclone Device Handbook
- Operating Requirements for Altera Devices Data Sheet

## Document Revision History

Table 4–53 shows the revision history for this chapter.

Table 4–53. Document Revision History							
Date and Document Version	Changes Made	Summary of Changes					
May 2008 v1.7	Minor textual and style changes. Added "Referenced Document" section.	_					
January 2007 v1.6	<ul> <li>Added document revision history.</li> <li>Added new row for V<sub>CCA</sub> details in Table 4–1.</li> <li>Updated R<sub>CONF</sub> information in Table 4–3.</li> <li>Added new Note (12) on voltage overdrive information to Table 4–7 and Table 4–8.</li> <li>Updated Note (9) on R<sub>CONF</sub> information to Table 4–3.</li> <li>Updated information in "External I/O Delay Parameters" section.</li> <li>Updated speed grade information in Table 4–46 and Table 4–47.</li> <li>Updated LVDS information in Table 4–51.</li> </ul>	<del>-</del>					
August 2005 v1.5	Minor updates.	_					
February 2005 v1.4	<ul> <li>Updated information on Undershoot voltage. Updated Table 4-2.</li> <li>Updated Table 4-3.</li> <li>Updated the undershoot voltage from 0.5 V to 2.0 V in Note 3 of Table 4-16.</li> <li>Updated Table 4-17.</li> </ul>	_					
January 2004 v.1.3	<ul> <li>Added extended-temperature grade device information. Updated Table 4-2.</li> <li>Updated I<sub>CC0</sub> information in Table 4-3.</li> </ul>	_					
October 2003 v.1.2	<ul> <li>Added clock tree information in Table 4-19.</li> <li>Finalized timing information for EP1C3 and EP1C12 devices. Updated timing information in Tables 4-25 through 4-26 and Tables 4-30 through 4-51.</li> <li>Updated PLL specifications in Table 4-52.</li> </ul>	_					

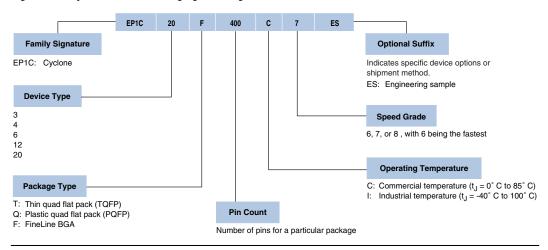


Figure 5-1. Cyclone Device Packaging Ordering Information

## Referenced Documents

This chapter references the following documents:

- Package Information for Cyclone Devices chapter in the Cyclone Device Handbook
- Quartus II Handbook

## Document Revision History

Table 5–1 shows the revision history for this chapter.

Table 5–1. Document Revision History						
Date and Document Version	Changes Made	Summary of Changes				
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_				
January 2007 v1.3	Added document revision history.	_				
August 2005 v1.2	Minor updates.	_				